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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known	
				Application Number	09/832,867
				Filing Date	April 12, 2001
				First Named Inventor	Shunpei YAMAZAKI et al.
				Group Art Unit	2822
				Examiner Name	M. Lewis
Sheet	1	of	1	Attorney Docket Number	0756-2294

U.S. PATENT DOCUMENTS						
Examiner Initials [*]	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ³ (if known)			
ML		5,108,935		Rodder	04/28/1992	
		5,241,203		Hsu et al.	08/31/1993	
		6,462,802		Nishimura et al.	10/08/2002	
		6,501,098		Yamazaki	12/31/2002	
ML		6,524,895		Yamazaki et al.	02/25/2003	

FOREIGN PATENT DOCUMENTS								
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ML		6,274,887		Yamazaki et al.	08/14/2001	
ML		6,573,195		Yamazaki et al.	06/03/2003	
ML		6,777,763		Zhang et al.	08/17/2004	

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Filing Date				April 12, 2001	
First Named Inventor				Shunpei YAMAZAKI, et al.	
Group Art Unit				2822	
Examiner Name				Monica Lewis	
Attorney Docket Number				0756-2294	
Sheet	1	of	3		

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		Number	Kind Code ³ (if known)			
MC		4,963,504		Huang	10/16/90	
		5,323,042		Matsumoto	06/21/94	
		5,399,502		Friend et al.	03/21/95	
		5,412,240		Inoue et al.	05/02/95	
		5,532,175		Racanelli et al.	07/02/96	
		5,543,340		Lee	08/06/96	
		5,543,947		Mase et al.	08/06/96	
		5,583,067		Sanchez	12/10/96	
		5,581,092		Takemura	12/03/96	
		5,585,295		Wu	12/17/96	
		5,594,569		Konuma et al.	01/14/97	
		5,637,519		Tsai et al.	06/10/97	
		5,686,328		Zhang et al.	11/11/97	
		5,767,930		Kobayashi et al.	06/16/98	
		5,757,444		Takemura	05/26/98	
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		5,851,861		Suzawa et al.	12/22/98	
		5,852,488		Takemura	12/22/98	
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		5,903,249		Koyama et al.	05/11/99	
		5,923,961		Shibuya et al.	07/13/99	
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		6,166,414		Miyazaki et al.	12/26/00	
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		6,211,536		Zhang	04/03/01	
		6,259,138		Ohtani et al.	07/10/01	
		6,274,400		Jen	08/14/01	
		6,274,887		Yamazaki et al.	08/14/01	
		6,277,679		Ohtani	08/21/01	

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		Filing Date	April 12, 2001
		First Named Inventor	Shunpei YAMAZAKI, et al.
		Group Art Unit	2822
		Examiner Name	Monica Lewis
Sheet 2 of 3	Attorney Docket Number	0756-2294	

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		Number	Kind Code ² (if known)		
ML		6,281,552		Kawasaki et al.	08/28/01
		6,284,577		Suzawa et al.	09/04/01
		6,303,963		Ohtani et al.	10/16/01
		6,306,694		Yamazaki et al.	10/23/01
		6,337,731		Takemura	01/08/02
		6,346,730		Kitakado et al.	02/12/02
		6,358,766		Kasahara	03/19/02
		6,362,507		Ogawa et al.	03/26/02
		6,365,917		Yamazaki	04/02/02
		6,384,808		Azami	05/07/02
		6,392,628		Yamazaki et al.	05/21/02
		6,399,988		Yamazaki	06/04/02
		6,407,430		Ohtani et al.	06/18/02
		6,420,200		Yamazaki et al.	07/16/02
ML		6,469,317		Yamazaki et al.	10/22/02

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
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ML		US Patent Application Serial No. 10/386,257 including specification, drawings, claims, and filing receipt; filed March 11, 2003; Inventor: Hideto Ohnuma.	
ML		US Patent Application Serial No. 09/454,146 including specification, drawings, claims, and filing receipt; filed December 3, 1999; Inventors: Shunpei YAMAZAKI, et al.	
ML		Yoshida et al., "A Full-Color Thresholdless Antiferroelectric LCD Exhibiting Wide Viewing Angle with Fast Response Time," SID 97 DIGEST, pp. 841-844.	ENG
ML		Hwang et al., "High Performance Submicron SOI/CMOS with an Elevated Source/Drain Structure," PROCEEDINGS OF THE ANNUAL SOS/SOI TECHNOLOGY CONFERENCE, IEEE, Vol. 19, 1993, pp. 132-133.	ENG
ML		Choi et al., "Gate-Overlapped Lightly Doped Drain Poly-Si Thin-Film Transistors for Large Area-AMLCD," IEEE TRANSACTIONS ON ELECTRON DEVICES, Vol. 45, No. 6, June, 1998, pp. 1272-1279.	ENG

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		Office ⁴	Number ⁴	Kind Code ⁵ (if known)				
ML		JP	04-369271		Takeda et al.	12/22/92		FULL
ML		JP	05-102483		Ueda	04/23/93		FULL
ML		JP	06-037314		Tsuchimoto	02/10/94		AB
ML		JP	07-202210		Taniguchi	08/04/95		AB
ML		JP	08-078329		Otani	03/22/96		AB
ML		JP	08-051207		Sato	02/20/96		AB
ML		JP	08-110530		Koyama et al.	04/30/96		AB
ML		JP	10-135469		Yamazaki et al.	05/22/98		AB
ML		JP	10-144929		Shibuya et al.	05/29/98		AB
ML		EP	0 451 968		Coxon	10/16/91		ENG
ML		JP	10-247735		Takano et al.	09/14/98		AB
ML		EP	0 803 911		Adan et al.	10/29/97		ENG
ML		JP	10-135468		Yamazaki et al.	05/22/98		AB

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ML		Tanaka, et al., "Ultrafast Operation of V _{th} -Adjusted p ⁺ -n ⁺ Double-Gate SOI MOSFET'S," IEEE Electron Device Letters, Vol. 15 (Oct., 1994), No. 10, pp. 386-388.	ENG
ML		Inui et al., "Thresholdless Antiferroelectricity in Liquid Crystals and its Application to Displays," J. Mater Chem., 1996, 6(4), pp. 671-673.	ENG
		Takada, et al., PROCEEDINGS OF 46 TH SPRING MEETINGS OF THE SOCIETY FOR APPLIED PHYSICS OF JAPAN, 28P-V-8, page 1316.	NONE
ML		Hwang et al., "Novel Polysilicon/TiN Stacked-Gate Structure for Fully-Depleted SOI/CMOS," IEDM '92, pp. 345-348.	ENG
		Yoshihara, EXISHO, Vol. 3, No. 3, pp. 190-194.	NONE
ML		Furue et al., "P-78: Characteristics and Driving Scheme of Polymer-Stabilized Monostable FLCD Exhibiting Fast Response Time and High Contrast Ratio with Gray-Scale Capability," SID '98 DIGEST, pp. 782-785.	ENG
ML		Hatano et al., "A Novel Self-Aligned Gate-Overlapped LDD Poly-Si TFT with High Reliability and Performance," IEDM '97, pp. 523-526.	ENG

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